

Microwave Makes Carbon Nanotubes less Defective

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Supporting Information

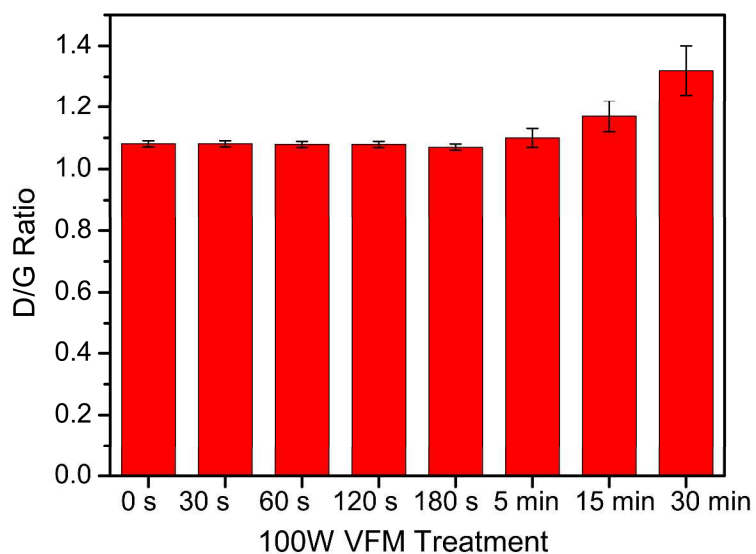


Figure S1. I_D/I_G of the VACNT samples treated by VFM with 100 W of power at varied duration.

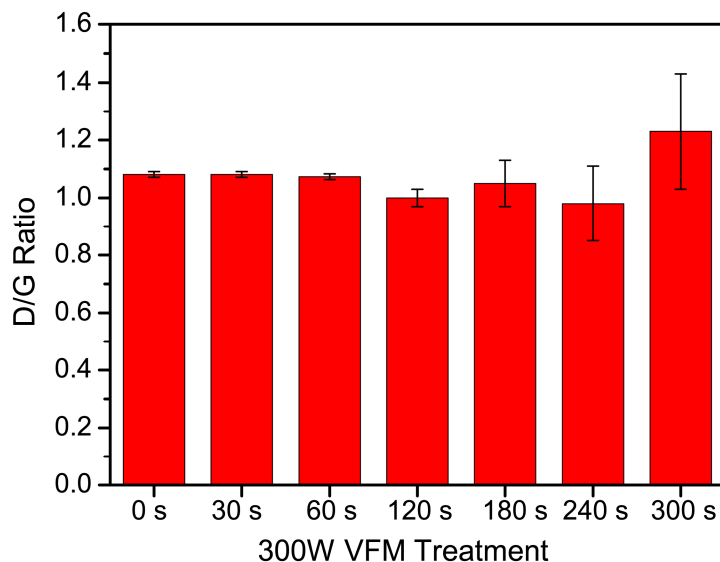


Figure S2. I_D/I_G of the VACNT samples treated by VFM with 300 W of power at varied duration.

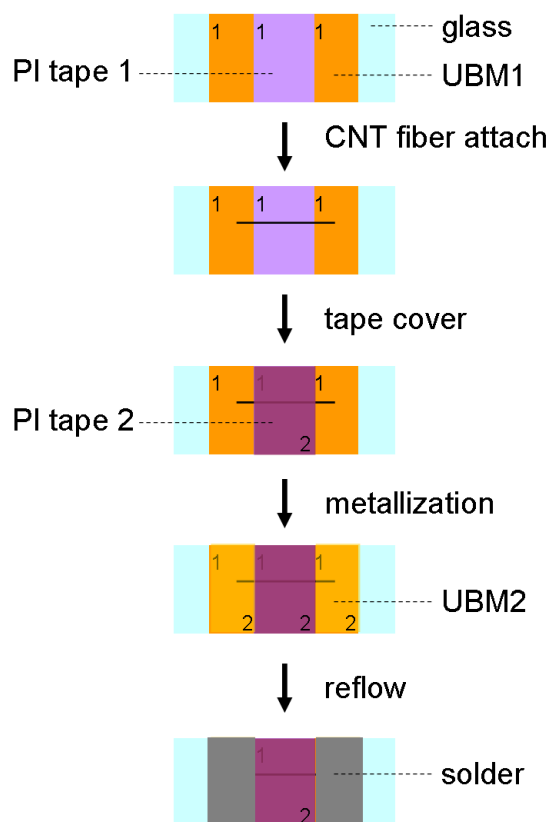


Figure S3. Illustration of the electrical conductivity measurement technique for an effective reduction of contact resistance. PI tape represents a double-sided polyimide tape; UBM represents under bump metallurgy layer, which is Au/Ni/Ti in this study.